(11) **EP 1 372 146 A8** 

(12)

## **CORRECTED EUROPEAN PATENT APPLICATION**

Note: Bibliography reflects the latest situation

(15) Correction information:

Corrected version no 1 (W1 A2)

INID code(s) 54

(51) Int Cl.<sup>7</sup>: **G11B 7/125**, G11B 11/105, G11B 7/24

(48) Corrigendum issued on: 10.03.2004 Bulletin 2004/11

(43) Date of publication:

17.12.2003 Bulletin 2003/51

(21) Application number: 03020494.5

(22) Date of filing: 11.05.2000

(84) Designated Contracting States: **DE FR GB NL** 

(30) Priority: **19.05.1999 JP 13806799 17.03.2000 JP 2000076514** 

(62) Document number(s) of the earlier application(s) in accordance with Art. 76 EPC: 00927745.0 / 1 182 649

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## Remarks:

This application was filed on 15 - 09 - 2003 as a divisional application to the application mentioned under INID code 62.

## (54) Optical recording method and medium.

(57) The present invention relates to an optical recording method for recording mark length modulated information with a plurality of recording mark lengths by irradiating a recording medium with a light, the optical recording method comprising a reduced number of divisions in the pulse division scheme.

Preferred phase change mediums are those having a recording layer containing excessive Sb in the SbTe eutectic composition. A particularly preferred composition contains excessive Sb and also Ge in the base  $Sb_{70}Te_{30}$  eutectic composition. The Sb/Te ratio is particularly preferably set to 4 or more. The content of Ge is preferably 10 atomic % or less. An example of such a recording layer is a  $M_zGe_y(SB_xTe_{1-x})_{1-y-z}$  alloy (where  $0\le z\le 0.1$ ,  $0< y\le 0.3$ ,  $0.8\le x$ ; and M is at least one of In, Ga, Si, Sn, Pb, Pd, Pt, Zn, Au, Ag, Zr, Hf, V, Nb, Ta, Cr, Co, Mo, Mn, Bi, O, N and S).